

Notice of References Cited	Application/Control No. 10/621,447		Applicant(s)/Patent Under Reexamination KWON ET AL.	
	Examiner Leila Malek		Art Unit 2611	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,990,160	01-2006	Abe et al.	375/355
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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